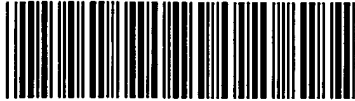


**Search Notes**

Application/Control No.

10/725,930

Examiner

TAN X. DINH

Applicant(s)/Patent under  
Reexamination

MATSUMI ET AL.

Art Unit

2627

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
Interference Search History Printout		1/24/2008	T.D

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST (see search history printout)	1/24/2008	T.D